

<b>Notice of References Cited</b>	Application/Control No. 10/521,718	Applicant(s)/Patent Under Reexamination NEERVOORT ET AL.	
	Examiner Thu V. Huynh	Art Unit 2178	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0227438	12-2003	Campbell et al.	345/156
*	B	US-2001/0040532	11-2001	YASUDA, HITOSHI	345/1.1
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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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